

Sandia National Laboratories SUMMIT V™ MEMS Process

Mature Technology with an Exciting Future

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Senior Member of Technical Staff**



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a wholly owned subsidiary of Lockheed Martin Corporation, for the U.S. Department of Energy's
National Nuclear Security Administration under contract DE-AC04-94AL85000.



Microsystems Engineering Sciences and Applications (MESA) Facility

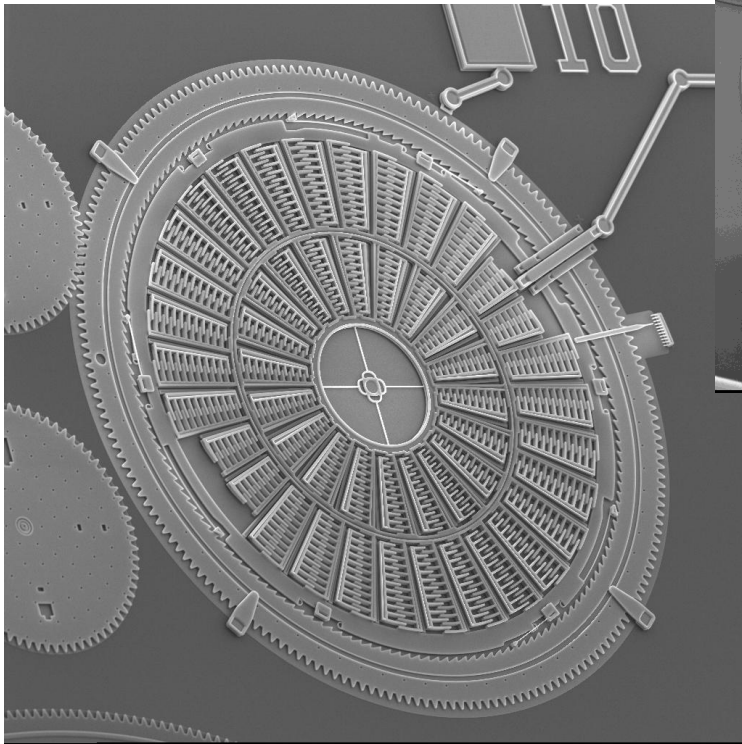
The SiFab at the MESA facility is a 150mm silicon wafer research and production facility for CMOS, MEMS, PV, and other microscale semiconductor products. The facility is a class-1 cleanroom with a highly trained production staff operating 24 hours, 5 days per week.



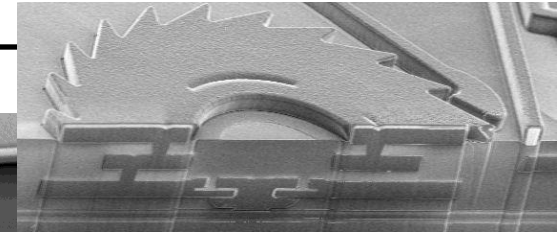


SUMMiT™ Process: Sandia Ultra-planar, Multi-level MEMS Technology Early Applications

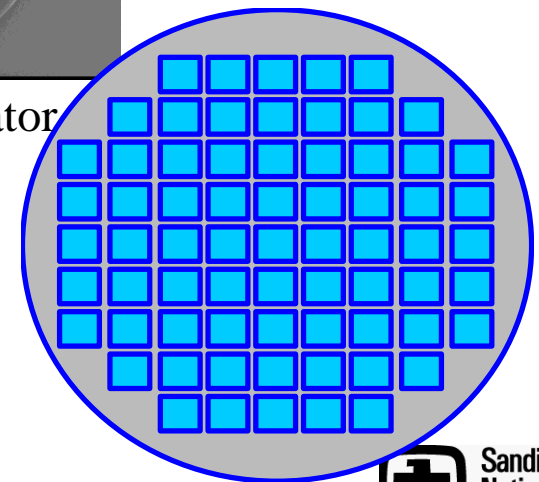
Torsional Rotational Actuator



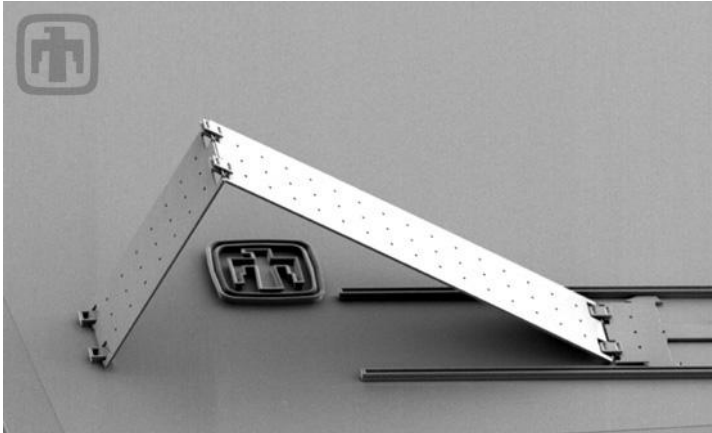
Double Ratchet Actuator



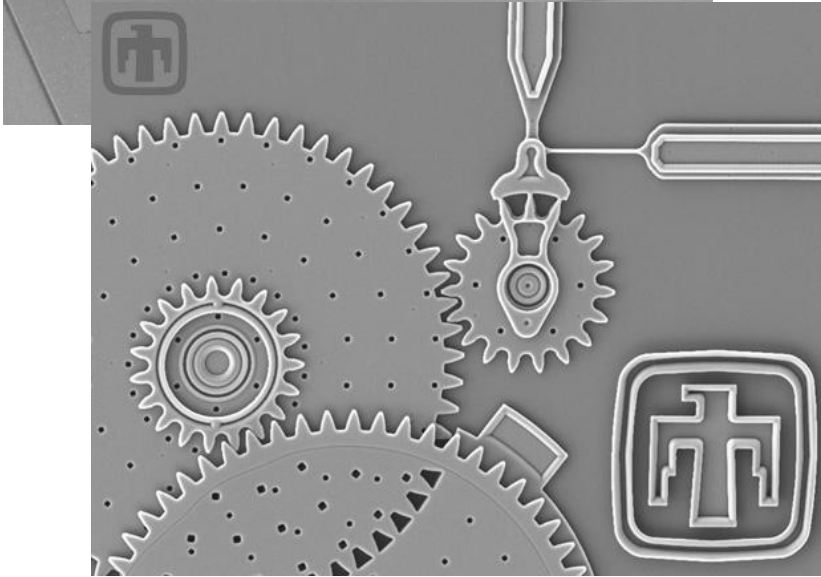
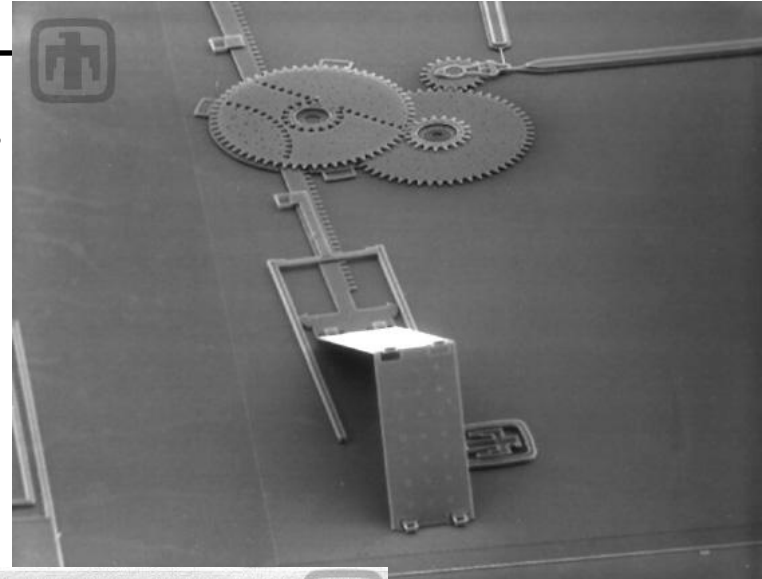
Cross-Section of a Pin
Joint Gear Hub



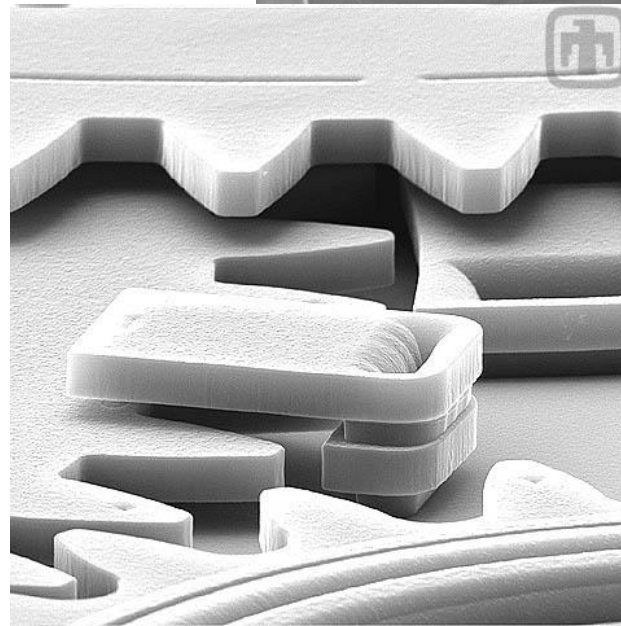
SUMMiT™ Process: Sandia Ultra-planar, Multi-level MEMS Technology Early Applications



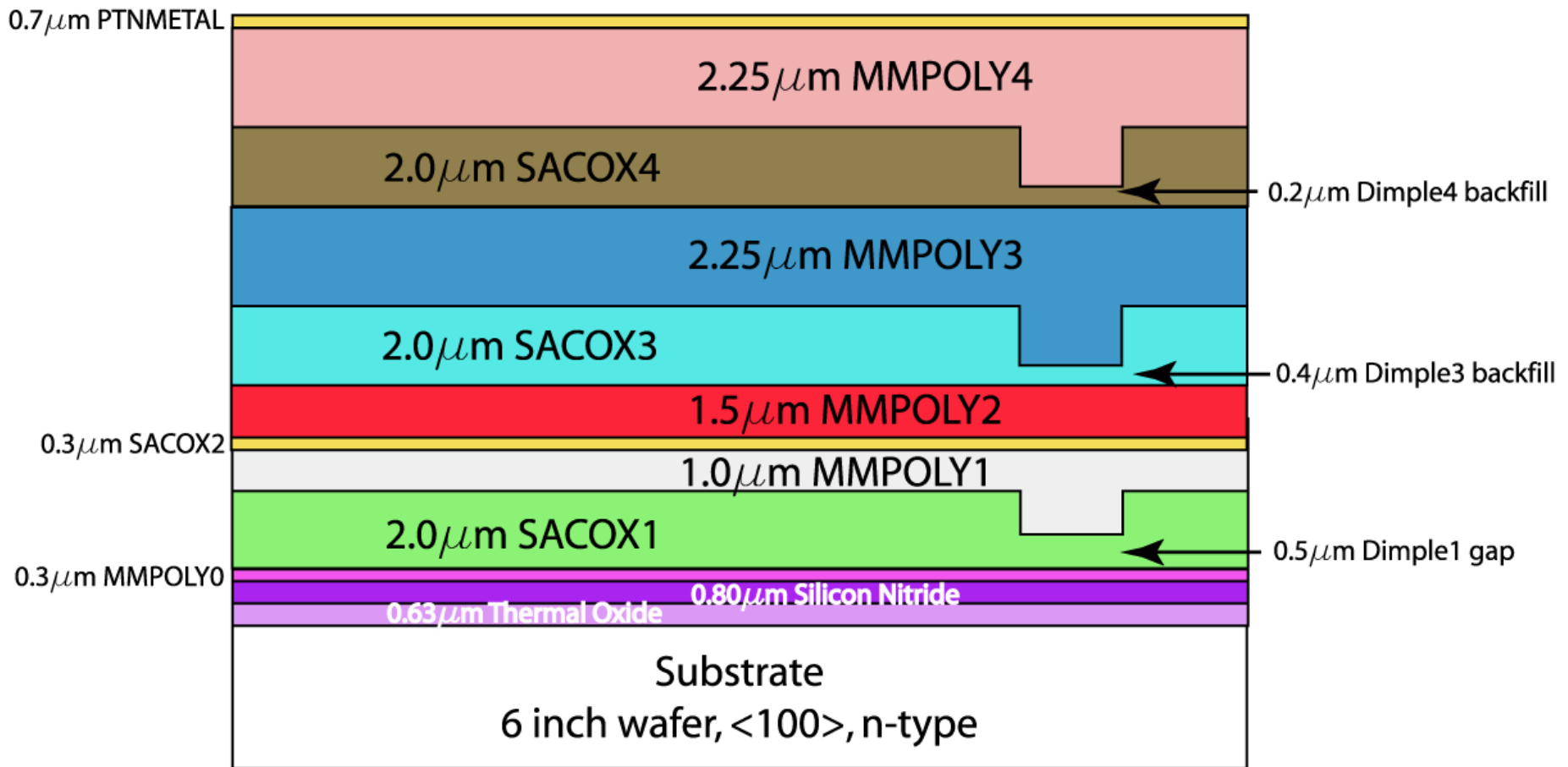
Hinged Pop-Up Mirrors



Gear Assemblies



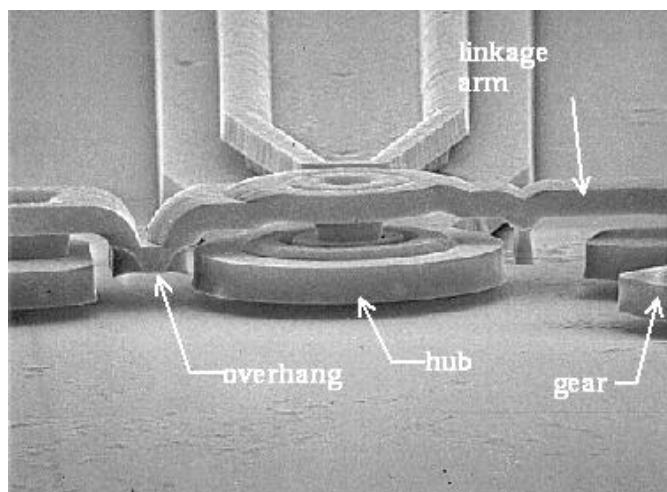
SUMMIT V™ Process Layers



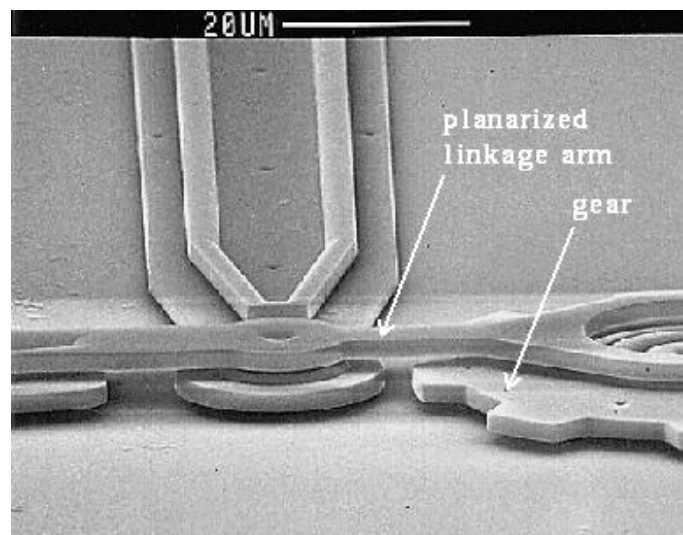
** All Polysilicon is doped with Phosphorus

CMP Process Comparison

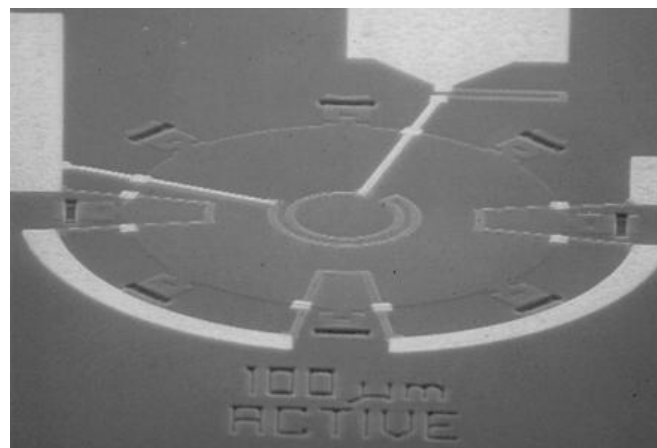
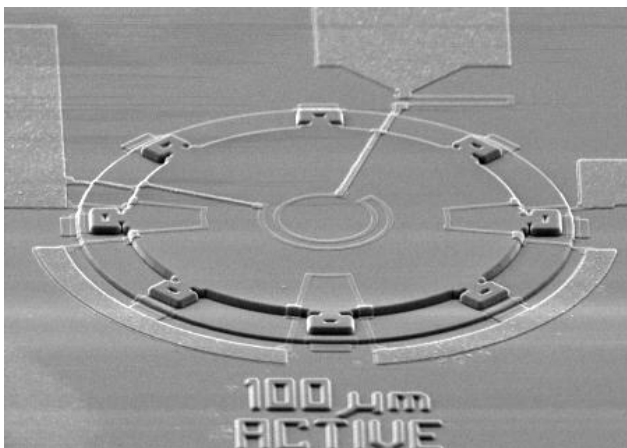
Non-planar Process



Planarized Process

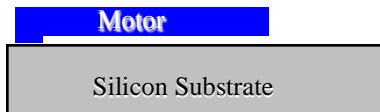
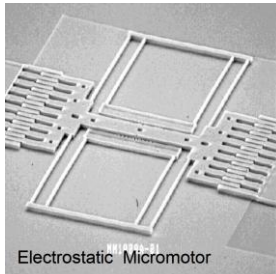


Pressure Sensor



Planarization Enabled a New Generation of Micromachines

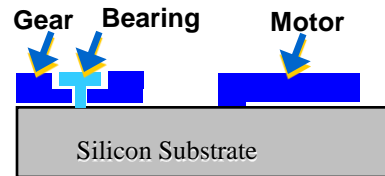
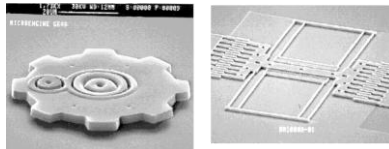
2*-Level



■ Polysilicon Level #1

Sensors

3-Level

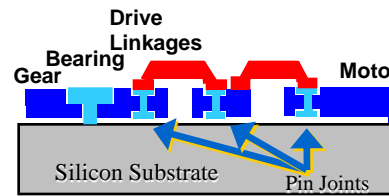
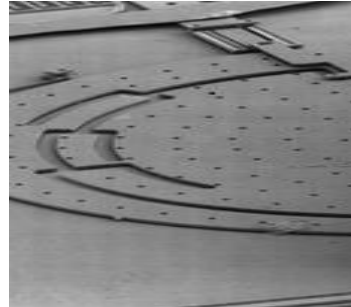


■ Polysilicon Level #1

■ Polysilicon Level #2

**Advanced
Sensors /
Simple Actuators**

4-Level



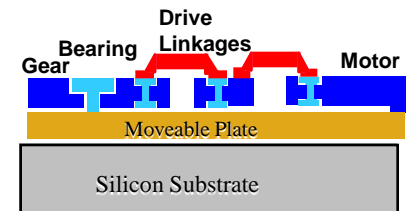
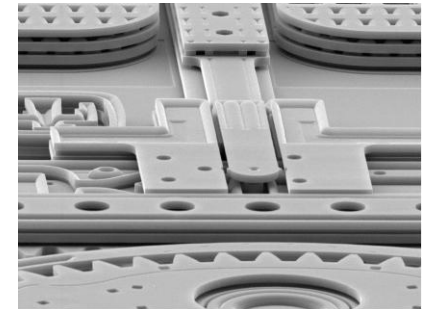
■ Polysilicon Level #1

■ Polysilicon Level #2

■ Polysilicon Level #3

**Advanced
Actuators**

5-Level



■ Polysilicon Level #1

■ Polysilicon Level #2

■ Polysilicon Level #3

■ Polysilicon Level #4

**Complex
Systems**

* First Poly level is
a ground plane

Competing technologies can be limited to only
two poly levels

Recent SUMMIT V™ Applications Beyond Gears

Active MEMS Polysilicon Microvalve for a Micro-Gas-Analyzer

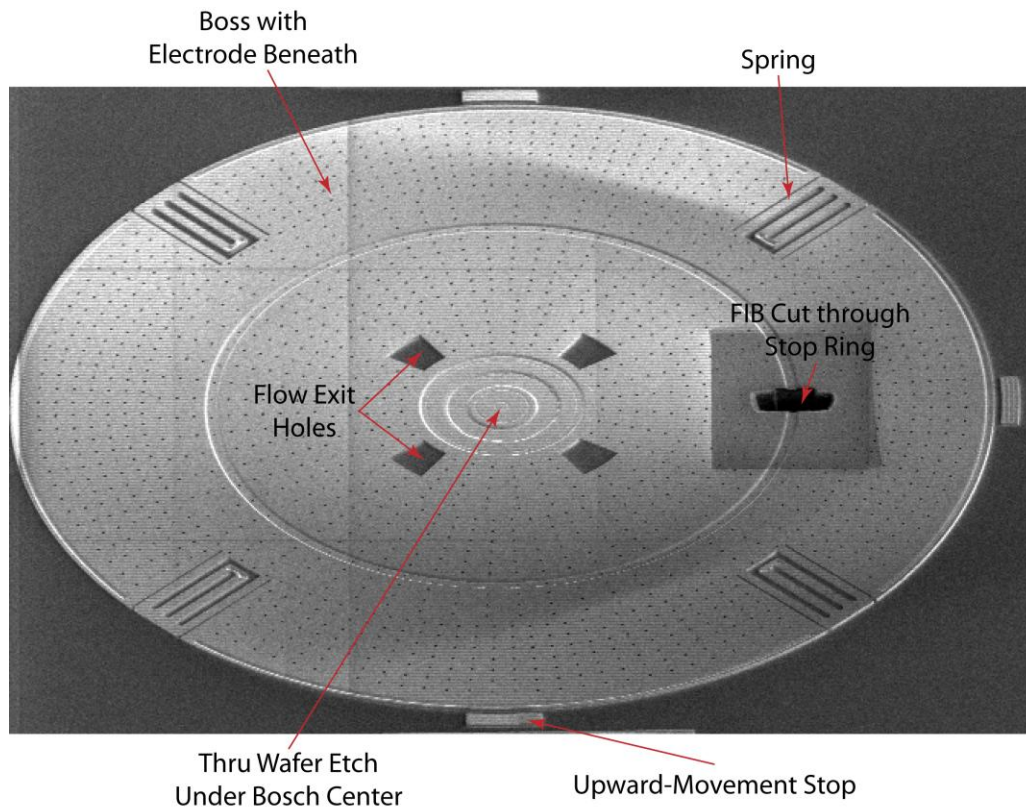
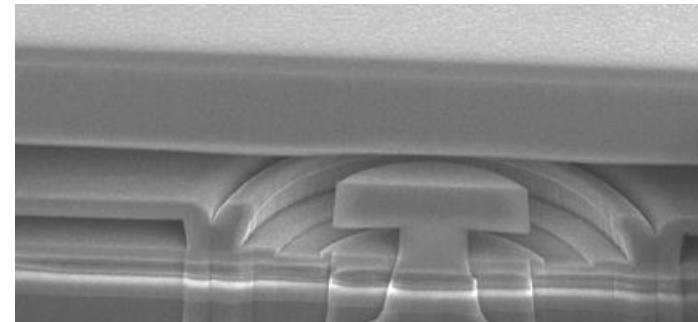
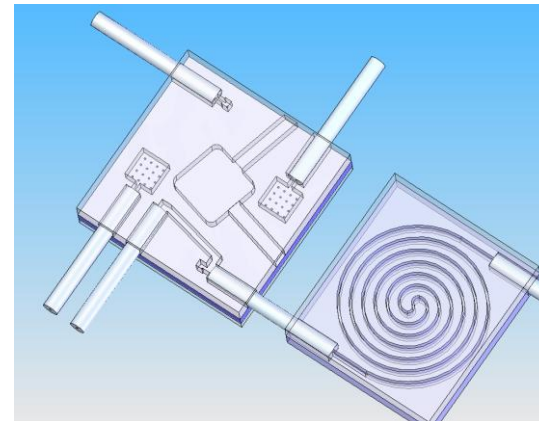


Figure 8: Active Valve SEM image



FIB cut SEM through valve stop



MGA

Check Valve

Fabricated Using SUMMiT V™ Based Processes

Passive MEMS Disk-in-Cage Poppet Microvalves

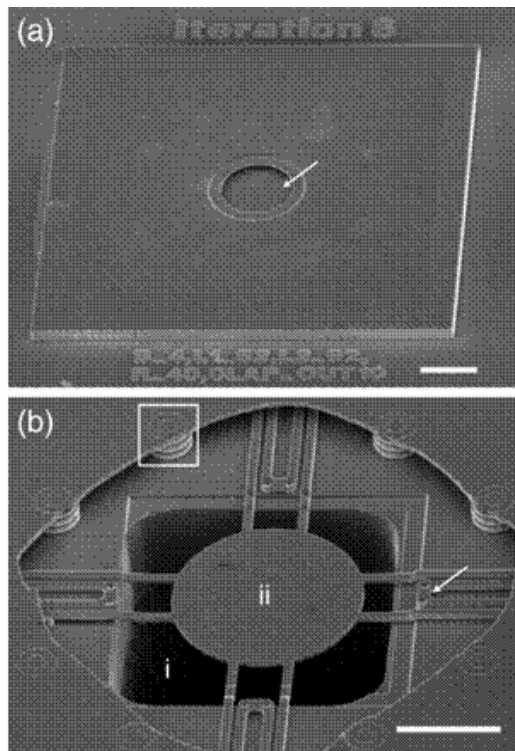


Figure 6: (a) SEM micrograph of an offset check-valve showing the outlet (arrow). (b) Valve with the cover removed to expose the valve inlet (i), body (boss) (ii), and springs. A lid anchor (box) and spring anchor (arrow) are noted. Scale bars = 50 μm .

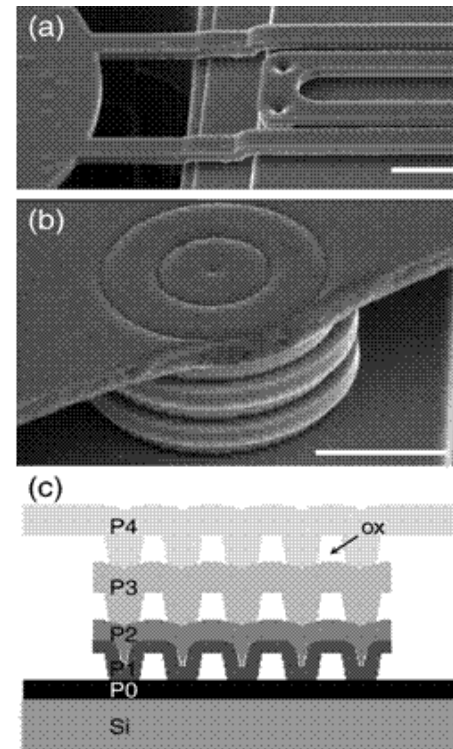
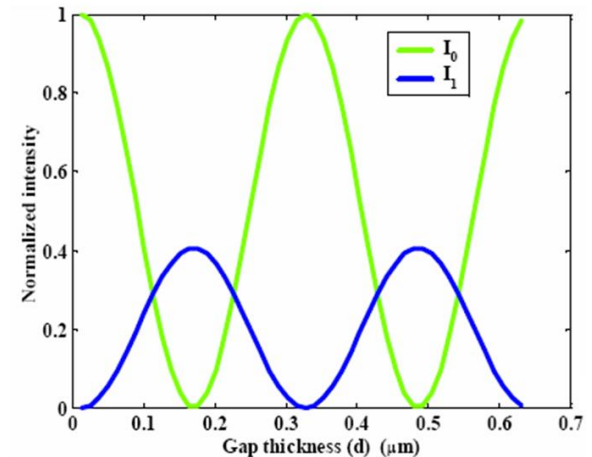
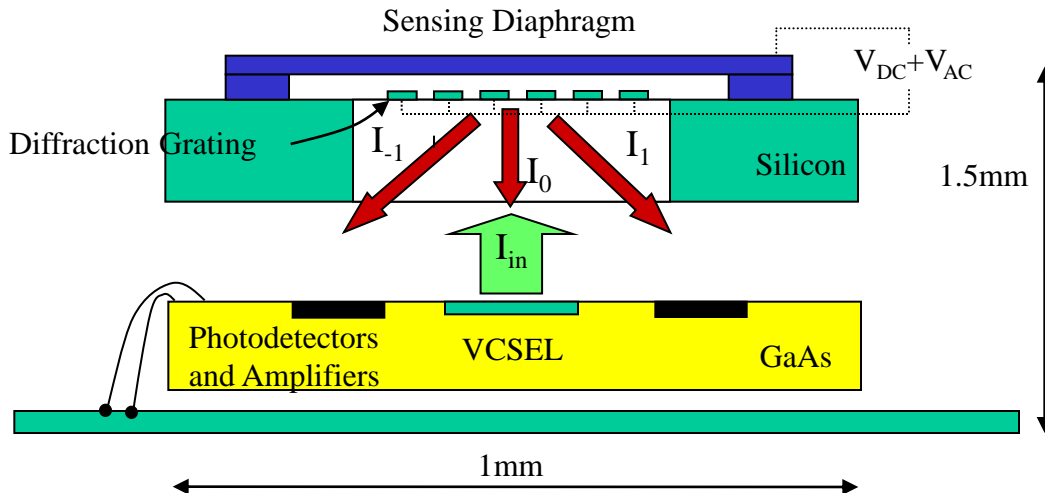
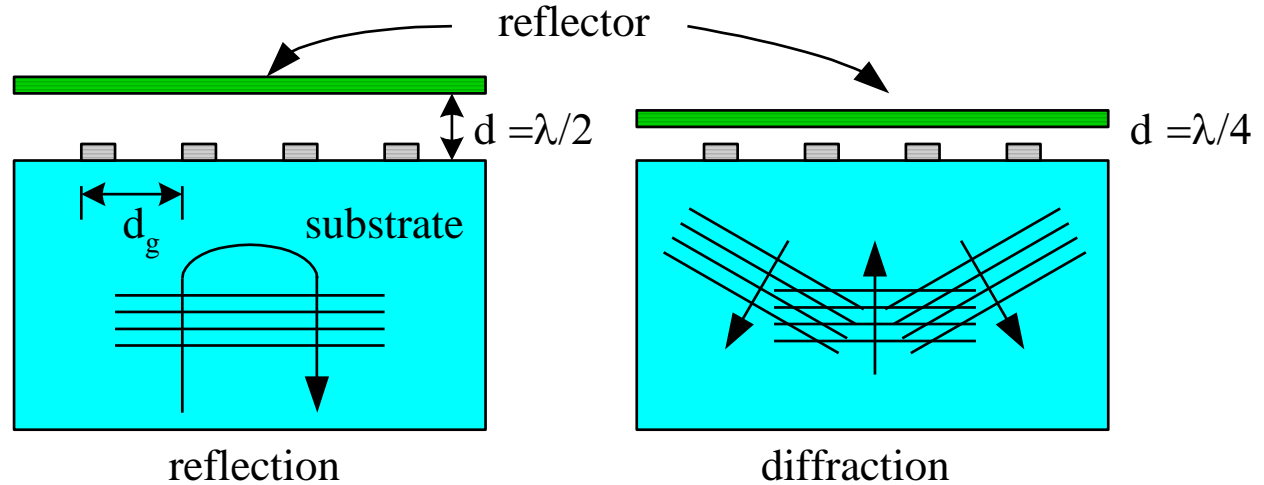


Figure 7: (a) Close-up of the spring anchor. Scale bar = 10 μm . (b) SEM micrograph of a lid anchor (box). Scale bar = 10 μm . (c) Schematic of the cross-section through the lid anchor showing the five polysilicon layers and trapped oxide (ox).

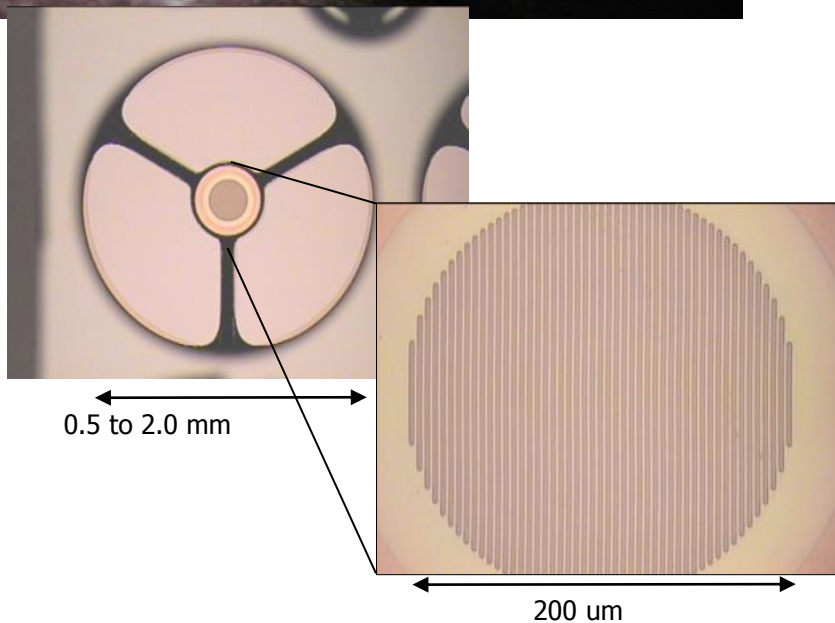
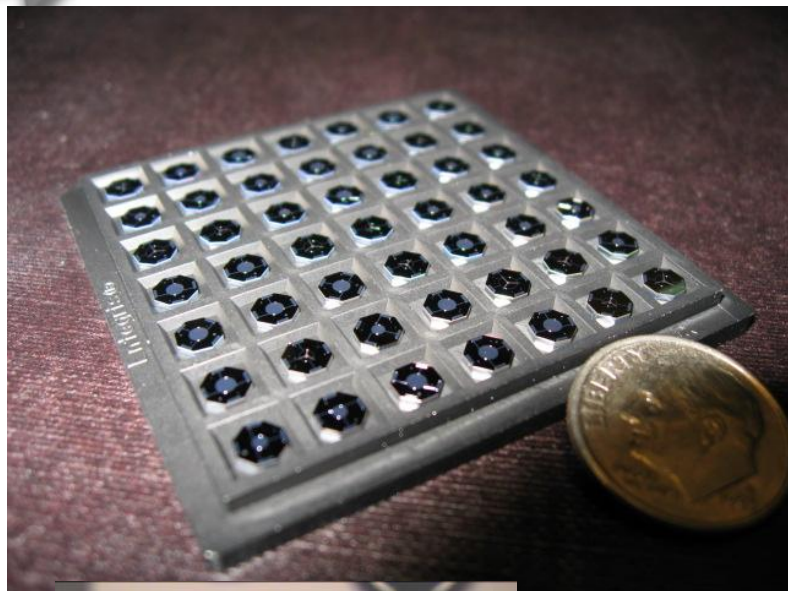
Optical Diffraction Microphone

Optical Measurement of Displacement

- Reflector displacement changes intensity of diffracted orders
- Excellent motion detector
- Very good optical modulator



Optical Diffraction Microphone Design



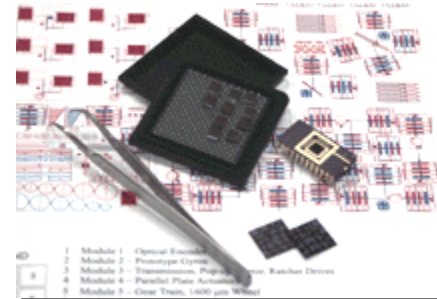
Gold Coating



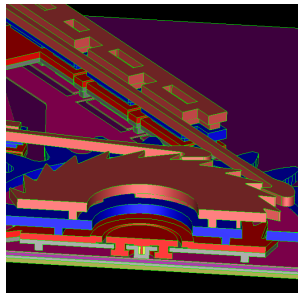
SAMPLES™: Sandia's Agile MEMS Prototyping, Layout Tools, Education, and Services



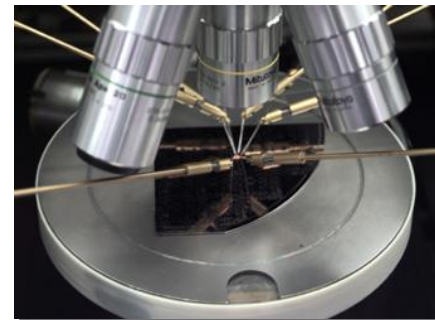
Education



Prototype Fabrication



Design Tools

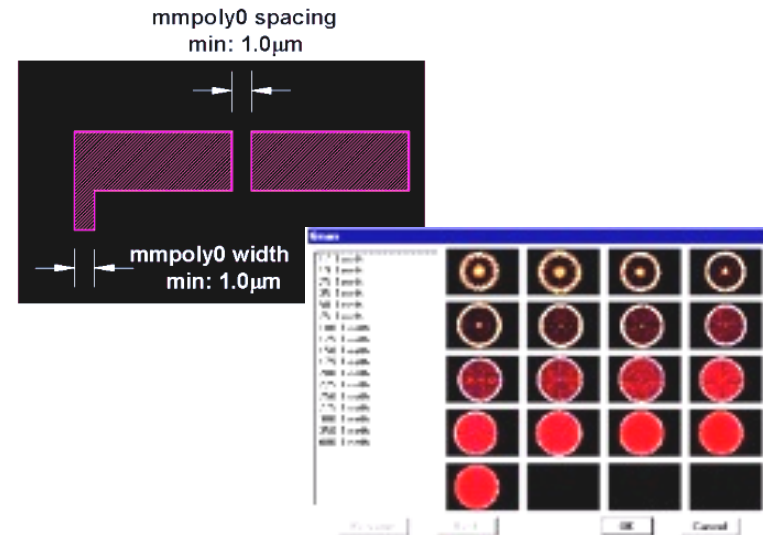


Services

**The SAMPLES™ Program Offers Ready,
Comprehensive Access to SUMMiT V™ Technology:**

SAMPLES: Design Layout & Visualization Tools

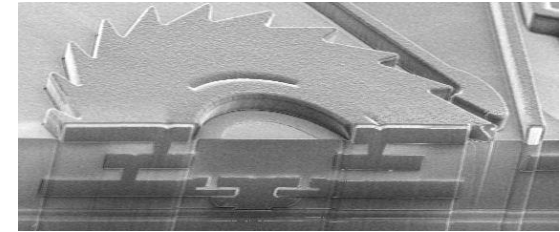
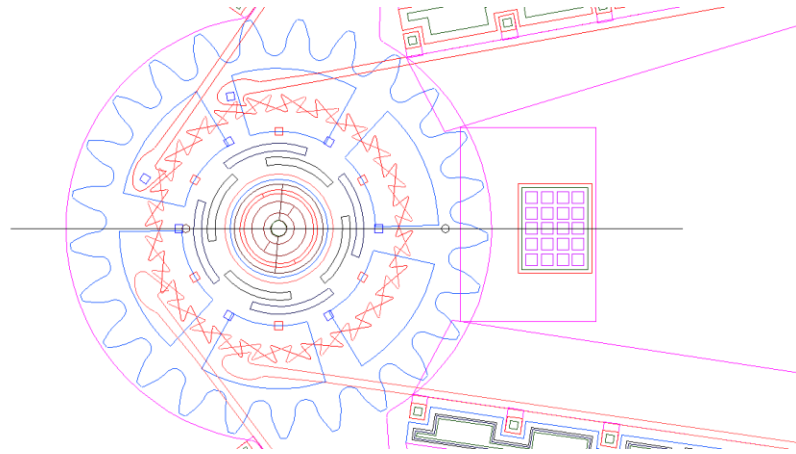
- Specific to SUMMiT V™ technology
- Integrated into AutoCAD environment
- Comprehensive suite of design tools
 - Advanced MEMS Design Tools software
 - Standard Components Library
 - Design Rule Checker
 - 2D Process Visualizer, 3D Visualizer Tools Software
 - 3D Modeler



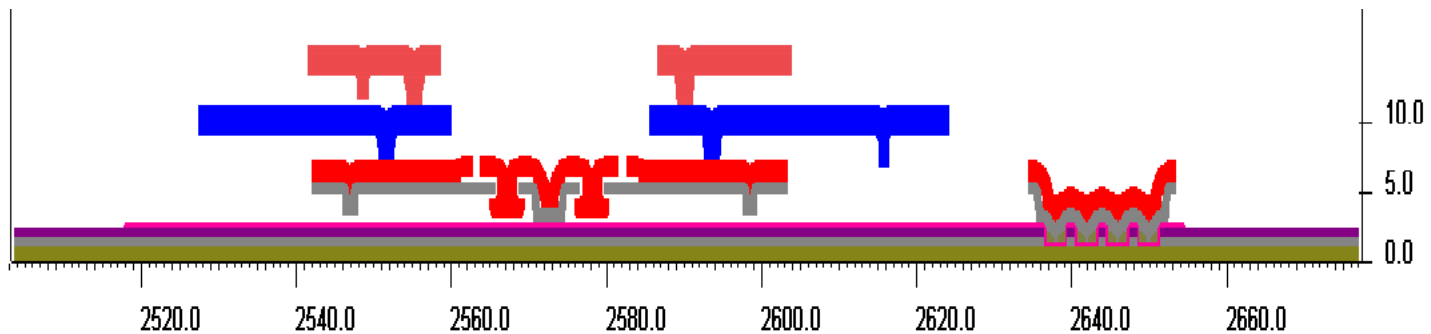
SUMMiT™ Process Cross-sections: Released Structure (Double Ratchet)



**SEM perspective
view of fabricated
device**

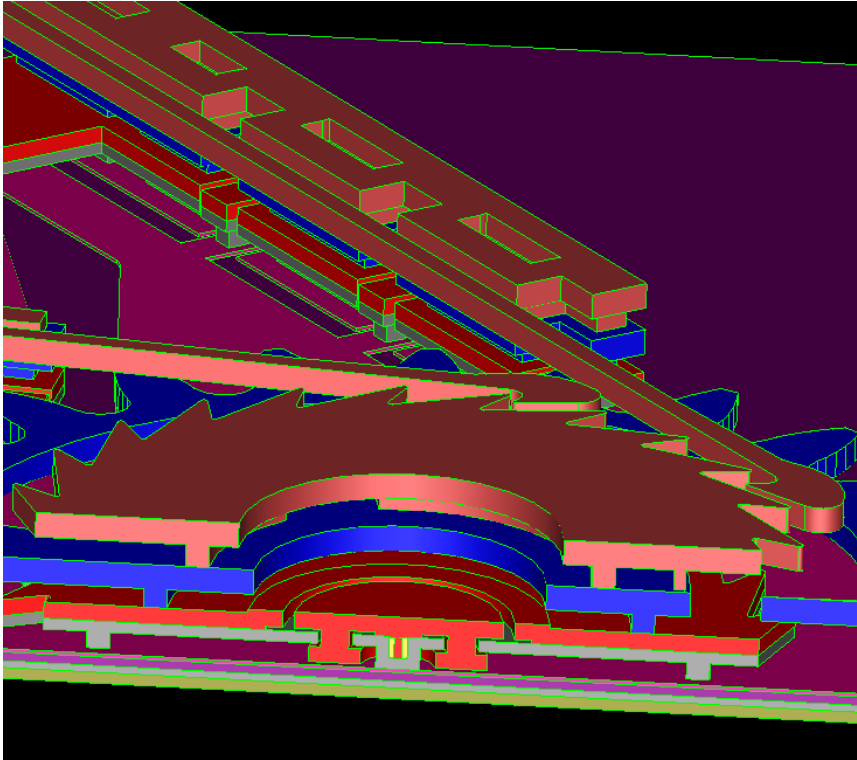


**FIB cross-section
of fabricated
device**

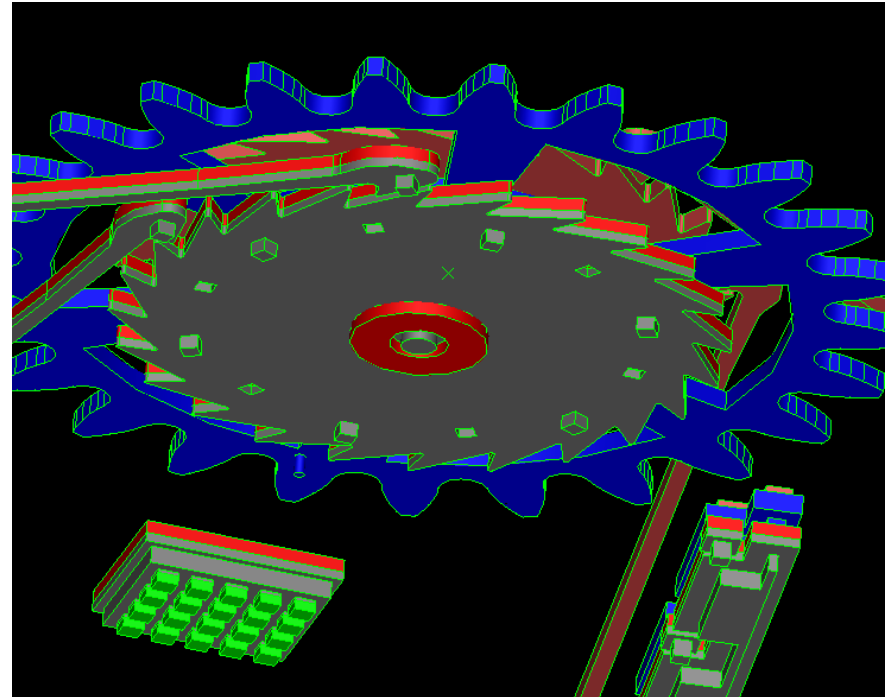


2D Visualizer Tool

SUMMIT V™ Process Cross-sections: Double Ratchet



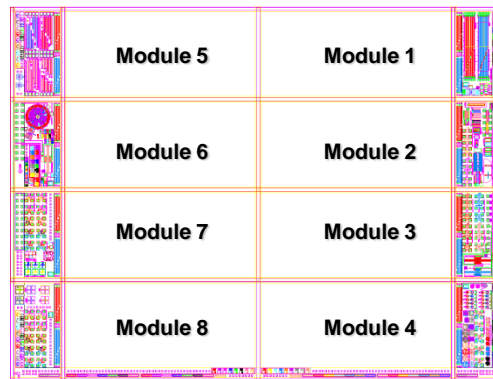
3D Visualizer Tool



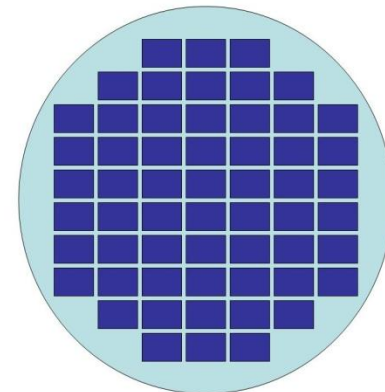
Using the SAMPLES™ Program to Prototype with SUMMiT V™ Technology

***SAMPLES™ modules are fabricated with the
SUMMiT V™ Process***

- Reticle size: 16500 μ X 12400 μ
- Diagnostic devices help characterize fab process
- Customer receives approximately 200 unreleased die
- Fabrication cost is shared among customers, \$17.2K per module



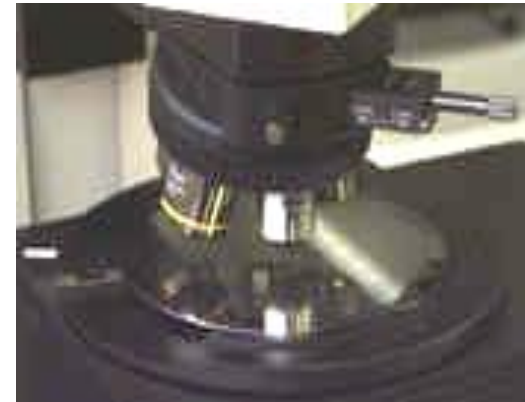
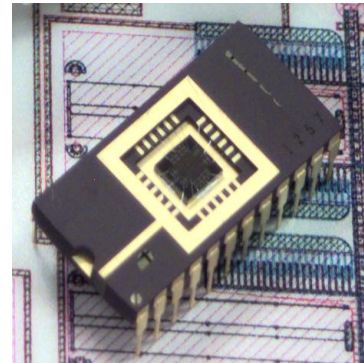
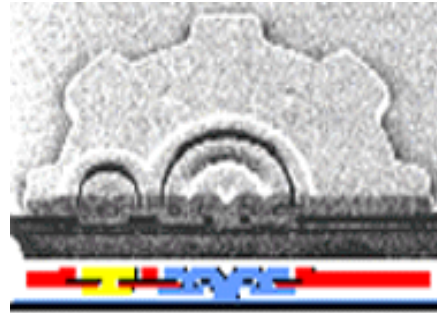
2820 μ X 6340 μ
modules



~ 58 die per wafer

SAMPLES: Additional Services Available

- Design Reviews
- Metallization
- Back-end processing
- Packaging
- Reliability characterization
- Failure Analysis
- Testing
- Individual specialized agreements
- Alternative processing available on a case by case basis





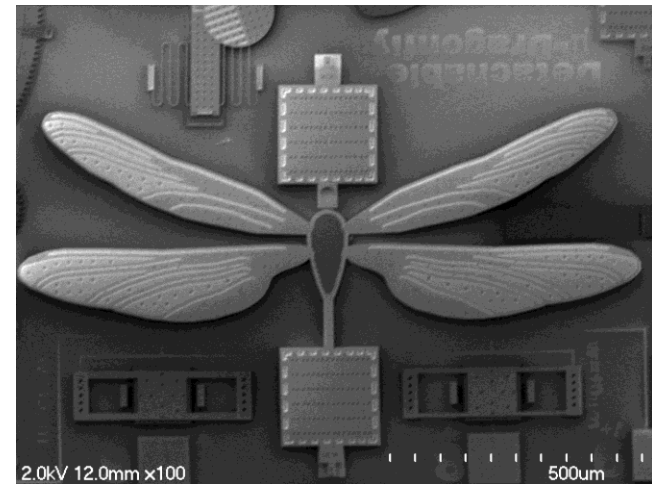
Sandia's MEMS University Alliance (UA): Leveraging the SAMPLES™ program

Highlights of the University Alliance License:

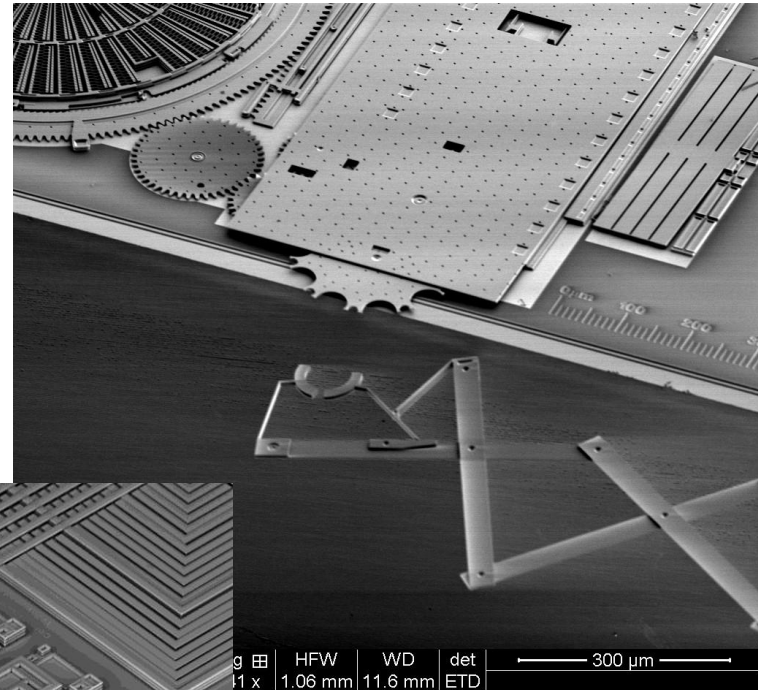
- **Site license for SUMMiT V™ Design and Visualization Tools**
 - For use in lab or classroom by course participants (1-50 students)
- **Training and technical support for a University POC to become a “Superuser”**
- **Opportunity to participate in the annual design contest**
- **MEMS parts for use in teaching**

**One-time License
Fee of \$5000**

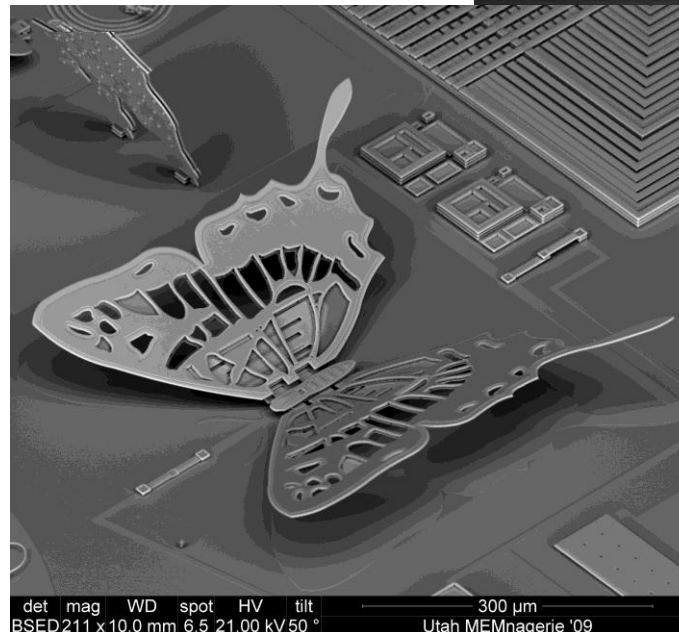
University Alliance Design Competition



Texas Tech



University of Utah





Useful Web Links

- Sandia National Laboratories MicroElectroMechanical Systems (MEMS)

<http://www.mems.sandia.gov/>

- Sandia National Laboratories University Alliance (UA) Program

<http://www.mems.sandia.gov/ua/index.html>

- University Alliance – Design Competition

<http://www.mems.sandia.gov/ua/contest.html>

- University Alliance – Member Resources

<http://www.mems.sandia.gov/ua/resources.html>

- Sandia National Laboratories SAMPLES Program

<http://www.mems.sandia.gov/samples/index.html>